

Impact of electrolyte incorporation in anodized niobium on its resistive switching

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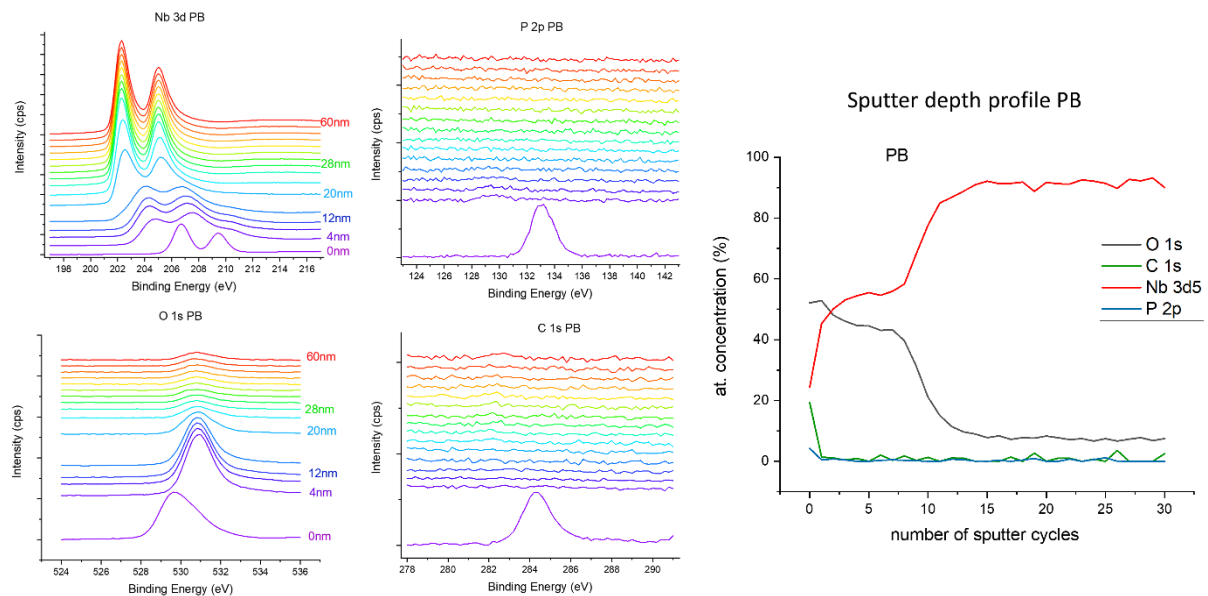


Figure S1: XPS depth sputtering profiles for anodic Nb memristors grown in phosphate buffer.

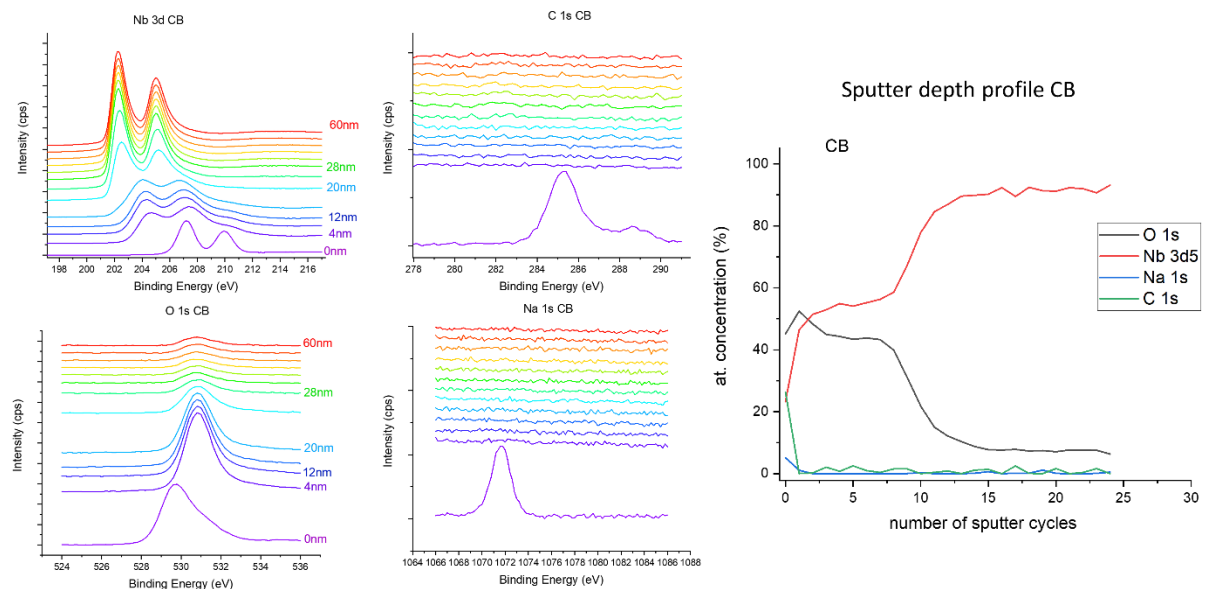


Figure S2: XPS depth sputtering profiles for anodic Nb memristors grown in citrate buffer.

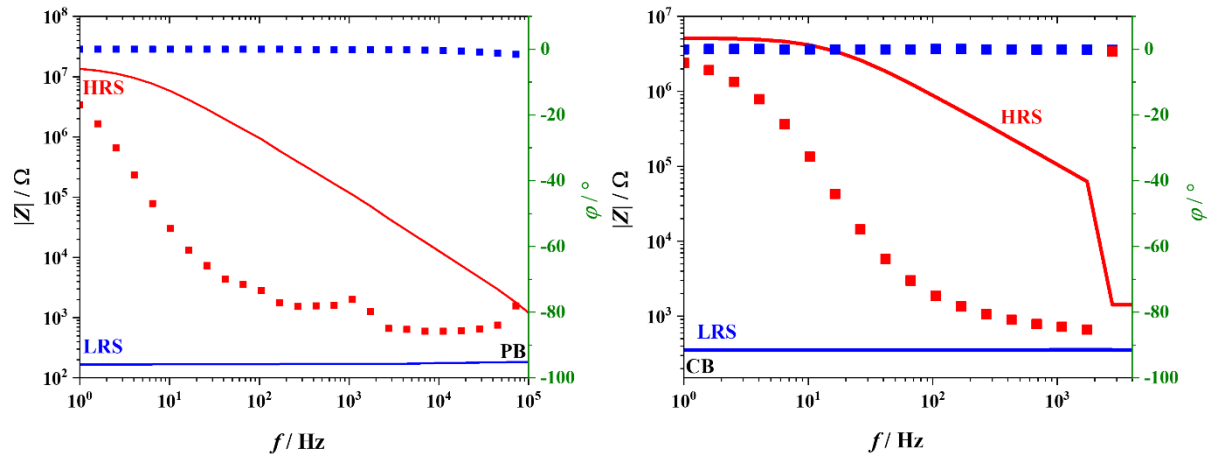


Figure S3: Impedance spectroscopy Bode plots of memristors grown in different electrolytes switched in LRS and HRS showing their impedance (full lines) and phase shift (dotted lines) dependence on frequency.